ON Semiconductor TEST PROCEDURE

## **TEST PROCEDURE for NCS21911 Evaluation Board**



# **ON Semiconductor**

NCS21911SN2GEVB

 ${\rm Rev}\ 0$ 

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## **BOARD ASSEMBLY DETAILS**

- The NCS21911 and test points for each pin are mounted on the top layer of the board.
- The two rows of headers are mounted on the bottom side of the board. The headers are accessible from the
  bottom side of the board and the narrow pitch of the exposed pins allows the board to be mounted on
  another board or receptacle.

## **TEST PROCEDURE**

## Check the connectivity

- 1. Use a multimeter to check the internal diode connection. Set the multimeter to the diode mode.
- 2. Put the positive probe on the VSS test point.
- 3. Keeping the positive probe on the VSS test point, place the negative probe on the VDD test point. The multimeter will indicate that it has sensed a diode by producing a sound and/or displaying the diode voltage drop. This indicates that the internal diode has been detected, and the pin is correctly connected.
- 4. Keep the positive probe on the VSS test point, and check the connection on IN-, IN+, and OUT by moving the negative probe to each of those test points.

## Connect the board

There are several options for connecting the board to a circuit:

- Connect to a breadboard or prototyping board with 2.54 mm spacing using the header pins
- Connect to a DIP-14 socket using the header pins
- Connect to any external circuit using the test points

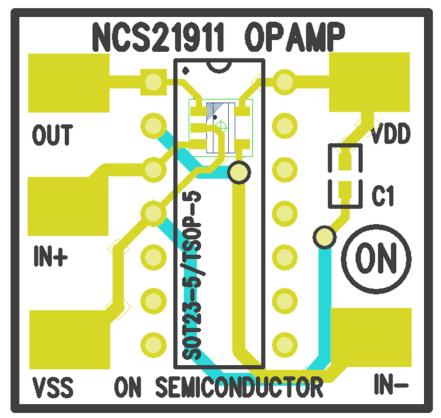


Figure 1: Board layout. The top layer is shown in blue. The bottom layer is shown in red.

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